

ELCOM (Electronics and Communications Abstracts)



- Subject Coverage**
- Circuits and Devices
 - Components and Materials
 - Control and Systems
 - Electronics and Communications Millieux
 - Phontonics
 - Power Systems
 - Telecommunications
 - Telecommunications Equipment and Instrumentation
 - Theoretical Electronics and Physics

File Type Bibliographic

- Features**
- | | | | | | |
|---------------------------------------|-------------------------------------|-----------------------|-------------------------------------|-----------------------------|--------------------------|
| Alerts (SDI) | Monthly | | | | |
| CAS Registry Numbers® | <input type="checkbox"/> | Page Images | <input type="checkbox"/> | STN AnaVist | <input type="checkbox"/> |
| Keep & Share | <input checked="" type="checkbox"/> | SLART | <input checked="" type="checkbox"/> | STN Easy | <input type="checkbox"/> |
| Learning Database | <input type="checkbox"/> | Structures | <input type="checkbox"/> | STN Viewer | <input type="checkbox"/> |

- Record Content**
- Bibliographic data
 - Abstract
 - Indexing

File Size • More than 1.0 million records (09/10)

Coverage • 1981 to the present

Updates Monthly

Language English

Database Producer Cambridge Scientific Abstracts
7200 Wisconsin Avenue
Bethesda, MD 20814 USA
Phone: (301) 961-6700
Phone: (800) 843-7751
Fax: (301) 961-6720
E-mail: support@csa.com

Sources Conference Proceedings, Dissertations, Government Reports, and Journal Articles

- User Aids**
- Cambridge Scientific Abstracts User's Manual (available from the producer)
 - Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
 - [STN Database Guide](#)

Clusters

- [ALLBIB](#)
 - [AUTHORS](#)
 - [COMPUTER](#)
 - [CORPSOURCE](#)
 - [CSAALL](#)
 - [ENGINEERING](#)
 - [MEETING](#)
 - [PHYSICS](#)
-

Pricing

See the [STN Price List](#) or enter HELP COST at an arrow prompt (=>).

Search and Display Field Codes

Fields that allow left truncation and SLART (/BI, /AB, /TI) in this file are indicated with an asterisk (*).

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index * (contains single words from the title (TI), abstract (AB), and uncontrolled terms (UT))	None (or /BI)	S SUPERCONDUCT? S HIGH TEMPERATURE/BI S FLIP (L) CHIP S ?GRAPH? (S) DISPLAY#	AB, TI, UT
Abstract *	/AB	S THROUGHPUT/AB S ?SYNCHRO?/AB	AB
Accession Number	/AN	S 2004:206066/AN	AN
Author	/AU	S SINGH S J/AU	AU
Classification Code (1) (code and text)	/CC	S 23.5/CC S SUPERCOND? DEVICE?/CC S "ANALOG AND HYBRID COMPUTERS"/CC	CC
Corporate Source (1)	/CS	S TRW/CS S TRW SPACE/CS	CS
Document Number	/DN	S "1992513 (EA)"/DN	DN
Document Type (code and text)	/DT	S CONFERENCE/DT S J/DT	DT
E-mail Address	/EML	S craig@physics.utah.edu/EML	EML
Entry Date (2)	/ED (or /UP)	S L1 AND ED>=20041219	ED
Field Availability	/FA	S AB/FA	Not displayed
File Segment (code and text)	/FS	S EN/FS S ELECTRONICS?/FS	FS
International Standard (Document) Number (contains ISSN and ISBN)	/ISN	S 9027720215/ISN S 0363-907X/ISN	ISN, SO
Journal Title	/JT	S COMP COMMUN/JT	JT, SO
Language (code and text)	/LA	S EN/LA S ENGLISH/LA	LA
Meeting Date (4)	/MD	S 20041001-20041010/MB	SO, MD
Meeting Location (4)	/ML	S ZVENIGOROD/ML	SO, MD
Meeting Title (4)	/MT	S MICRO/MT	SO, MT
Meeting Year (4)	/MY	S 2005/MY	SO
Note (3)	/NTE	S CHIP?/NTE S ?SYNC?/NTE	NTE
Number of Report	/NR	S NASA/NR S NASA-TP-2407/NR	NR, SO
Publication Date (2)	/PD	S PD>19990100	SO
Publication Year (2)	/PY	S 1999-2000/PY	PY, SO
Publisher (4)	/PB	S SPRINGER/PB	PB
Reference Count (2)	/REC	S 100-110/REC	REC
Source (contains journal title, meeting information, collation (volume, number, page numbers), publisher and location, publication date, contract or report number, ISSN, ISBN)	/SO	S (COMP COMMUN? AND VOL 14)/SO S 8755-6332/SO	SO
Summary Language (code and text)	/SL	S ENGLISH/SL S EN/SL	SL
Title	/TI	S HIGH T/TI	TI

- (1) Search with implied (S) proximity is available in this field.
(2) Numeric search field that may be searched using numeric operators or ranges.
(3) Currently empty field.
(4) Field added May 2005, new data only.

ELCOM**DISPLAY and PRINT Formats**

Any combination of formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for all fields except PY. Highlighting must be ON during SEARCH in order to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB AN AU CC CS DN DT ED EML FS ISN (1) JT (1) JTA (1) LA MD ML MT NR (1) NTE PB (1) PY (1) REC SL SO TI UP UT	Abstract Accession Number Author Classification Code Corporate Source Document Number Document Type Entry Date E-mail Address File Segment International Standard (Document) Number Journal Title Journal Title, Abbreviation Language Meeting Date Meeting Location Meeting Title Number of Report Note Publisher Publication Year Reference Count Summary Language Source Title Update Date Uncontrolled Term	D L4 1-4 AB D L1 3 AN D AU 1,3-5 D CC 5-10 D 1-3,7,8 CS D DN D DT D ED D EML D FS 1-5 D L1 ISN 3 D 1,3,6,8 JT L5 D JTA D LA D MD D ML D MT D L1 NR D NTE D PB D PY 3,4 D REC 6-8 D SL D SO D TI TOTAL D UP D UT 2
ABS ALL BIB CBIB DALL FREE (2) IALL IBIB IND SAM SCAN (2,3) TRIAL (2)	AB AN, DN, TI, AU, CS, SO, DT, FS, LA, SL, NTE, REC, ED, AB, CC, UT AN, DN, TI, AU, CS, SO, DT, FS, LA, SL NTE, REC, ED (default) Compressed bibliographic information ALL, delimited for post-processing TI, CC, UT ALL, indented with text labels BIB, indented with text labels CC, UT TI, CC, UT TI, CC, UT (random display without answer number) TI, CC, UT	D ABS D 1-5 ALL D BIB D CBIB D 1-5 IALL D FREE D 1-5 IALL D IBIB D 1-10 CBIB IND D 1, 5, 10 SAM D SCAN D TRI 10 L7
HIT KWIC OCC (2)	Fields containing hit terms Hit terms with 20 words on either side (KeyWord-In-Context) Number of occurrences of hit terms and fields in which they occur	D 1 5 10 HIT D KWIC NOH D OCC

(1) Custom display only.

(2) No online display charge for this format.

(3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Author	AU	Y	Y
Citation	CIT	Y	N
Classification Code	CC	Y	Y
Corporate Source	CS	Y	Y
Document Number	DN	Y	N
Document Type	DT	Y	Y
E-mail Address	EML	Y	Y
Entry Date	ED	Y	Y
File Segment	FS	Y	Y
International Standard Book Number	ISBN	N	Y
International Standard (Document) Number	ISN	Y (3)	Y
International Standard Serial Number	ISSN	N	Y
Journal Title	JT	Y	Y
Journal Title, Abbreviation	JTA	Y	Y
Language	LA	Y	Y
Meeting Date	MD	Y	Y
Meeting Location	ML	Y	Y
Meeting Title	MT	Y	Y
Note	NTE	Y	Y
Number of Report	NR	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y (5)	Y
Publisher	PB	Y	Y
Reference Count	REC	Y	Y
Source	SO	Y (6)	N
Summary Language	SL	Y	Y
Title	TI	Y (default)	Y
Uncontrolled Term	UT	Y (2)	N
Update Date	UP	Y	Y

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /BI to the terms created by SELECT.
- (3) Selects or analyzes the ISSN and ISBN with /ISN appended to the terms created by SELECT.
- (4) Selects or analyzes the patent number with /PN appended to the terms created by SELECT.
- (5) SELECT HIT and ANALYZE HIT are not valid with this field.
- (6) Selects or analyzes the ISSN and ISBN with /SO appended to the terms created by SELECT.

Sample Records

DISPLAY IALL

ACCESSION NUMBER: 2010:198095 ELCOM [Full-text](#)
 DOCUMENT NUMBER: 201009-40-13336268 (EA)
 TITLE: Rejection of persistent-bounded disturbances in continuous time-delay systems using observer-based feedback
 AUTHOR: Mahmoud Magdi S; Saif Abdul-Wahid
 CORPORATE SOURCE: Systems Engineering Department, King Fahd University of Petroleum and Minerals, P. O. Box 985, Dhahran 31261, Saudi Arabia. msmahmoud@kfupm.edu.sa
 SOURCE: Optimal Control Applications and Methods, Vol. 31, No. 2, pp. 171-182, 20100300.
 ISSN: 0143-2087.
 DOCUMENT TYPE: Journal; Article; (Journal Article)
 FILE SEGMENT: Electronics & Communications Abstracts
 LANGUAGE: English
 ENTRY DATE: Entered STN: 14 Sep 2010
 Last Updated on STN: 14 Sep 2010
 ABSTRACT: In this paper, the problem of persistent-bounded disturbance rejection of linear continuous-time systems with time-varying delays is investigated using the tools of invariant set analysis and Lyapunov-function methodology. We derive less conservative sufficient conditions on robust attractor for time-delay systems in terms of strict linear matrix inequalities (LMIs) to guarantee the desired 1-performance. A robust output-feedback controller is designed and the associated gain is determined using strict LMIs. The developed results are tested on two representative time-delay examples.
 CLASSIFICATION: 40 Control and Systems (General)
 UNCONTROLLED TERM: Control systems; Control theory; Delay; Disturbances; Feedback; Gain; Invariants; Rejection

DISPLAY BIB

AN 2010:198108 ELCOM [Full-text](#)
 DN 201009-40-13336281 (EA)
 TI A reinforcement learning-based scheme for direct adaptive optimal control of linear stochastic systems
 AU Wong Wee Chin; Lee Jay H
 CS School of Chemical and Biomolecular Engineering, Georgia Institute of Technology, Atlanta, GA 30332, U.S.A.. jay.lee@chbe.gatech.edu
 SO Optimal Control Applications and Methods, Vol. 31, No. 4, pp. 365-374, 20100700.
 ISSN: 0143-2087.
 DT Journal; Article; (Journal Article)
 FS Electronics & Communications Abstracts
 LA English
 ED Entered STN: 14 Sep 2010
 Last Updated on STN: 14 Sep 2010

DISPLAY IND

L6 ANSWER 12 OF 32944 ELCOM COPYRIGHT 2010 Cambridge Scientific Abstracts on STN
 CC 40 Control and Systems (General)
 UT Adaptive control systems; Algorithms; Linear systems; Mathematical models; Optimal control; Optimization; Reinforcement; Stochastic systems

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

CAS Customer Care:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
E-mail: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany

Phone: +49-7247-808-555
Fax: +49-7247-808-259
E-mail: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.de

In Japan

JAICI (Japan Association for
International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan

Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
E-mail: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp